

Supporting Information for:

Discovery of a Tetracontinuous, Aqueous Lyotropic Network Phase with Unusual 3D-Hexagonal Symmetry

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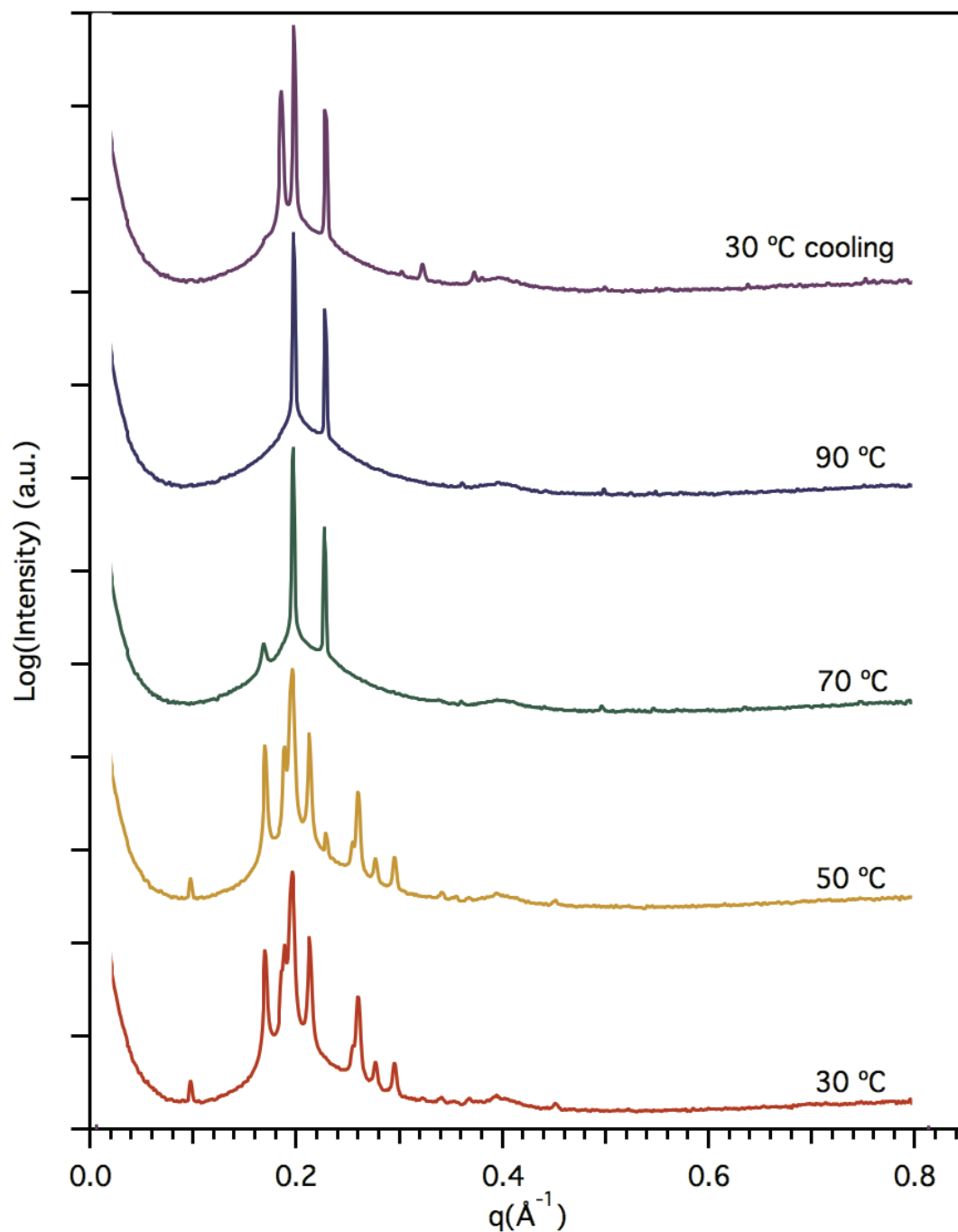


Fig. S1. Azimuthally-integrated synchrotron SAXS patterns for aqueous LLCs derived from 57.5 wt% **Na-94** in H₂O between $T = 30$ - 90 °C. A thermoreversible order-to-order transition is observed between 50-70 °C from the H_I¹⁹³ to G_I. The kinetics of this transition are slow, as evidenced by only partial phase reversion upon cooling to 30 °C and annealing for 5 min.

Table S1. Table of positions of the observed reflections ($q_{\text{obs}}(\text{\AA}^{-1})$ and $2\theta_{\text{obs}}(^{\circ})$) from cell refinement of **Na-94** 57.5 wt% at 40 °C to $P6_3/mcm$ symmetry and lattice constants of $a = b = 7.37$ nm and $c = 6.63$ nm using the Jade 5 software package (Materials Data, Inc.), along with the angular residuals. For a three-dimensional hexagonal lattice, $q^2 = (4/3)(h^2 + k^2 + hk) + (1/R^2)l^2$, where $R = c/a$.(21)

<i>hkl</i>	$q_{\text{obs}} (\text{\AA}^{-1})$	$2\theta_{\text{obs}} (^{\circ})$	$2\theta_{\text{cal}} (^{\circ})$	Residual = $2\theta_{\text{calc}} - 2\theta_{\text{obs}} (^{\circ})$
100	0.0989	0.927	0.927	0
110	0.1715	1.607	1.606	-0.001
002	0.1906	1.786	1.785	0
111	0.1963	1.839	1.837	-0.002
200	0.1977	1.853	1.854	0.001
102	0.2146	2.011	2.012	0.001
112	0.2564	2.403	2.401	-0.001
210	0.2619	2.454	2.453	-0.001
202	0.2749	2.576	2.574	-0.002
211	0.2786	2.611	2.611	0
300	0.2969	2.782	2.782	0
212	---	---	3.034	
113	0.3330	3.121	3.123	0.001
220	0.3430	3.214	3.212	-0.002
302	0.3527	3.305	3.306	0
221	---	---	3.334	
310	0.3564	3.34	3.343	0.004
311	0.3693	3.461	3.461	-0.001
004	---	---	3.571	
213	---	---	3.632	
222	---	---	3.675	
104	---	---	3.689	
400	0.3958	3.709	3.709	0
312	---	---	3.79	
114	---	---	3.916	
204	0.4293	4.023	4.024	0
320	0.4314	4.043	4.042	0
402	---	---	4.117	
321	---	---	4.14	
223	---	---	4.183	
410	0.4535	4.25	4.25	0
313	---	---	4.284	

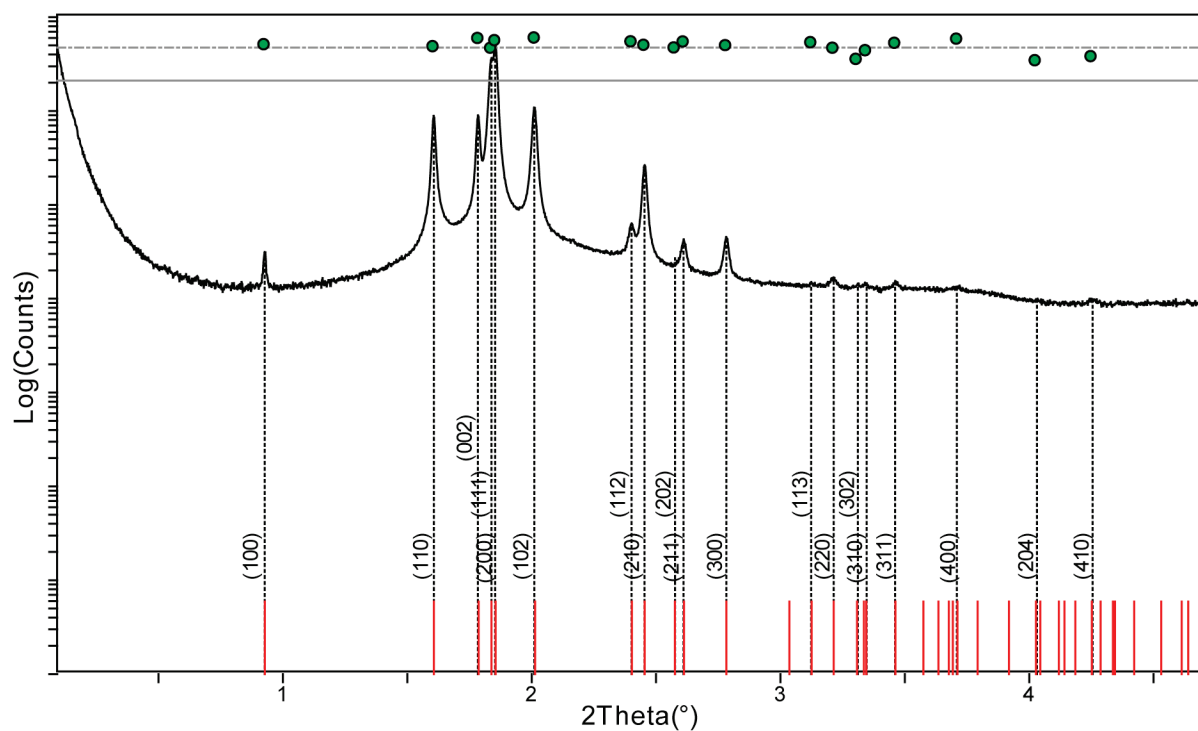


Fig. S2. Azimuthally integrated X-ray scattering pattern for 57.5 wt% **Na-94** in H₂O at 40 °C with observed reflections (---), calculated reflection positions (-), and (*hkl*) indices for a unit cell with *P6₃/mcm* symmetry and lattice constants of *a* = *b* = 7.37 nm and *c* = 6.63 nm. Fitting was performed using the cell refinement function in Jade 5 software package (Materials Data, Inc.).

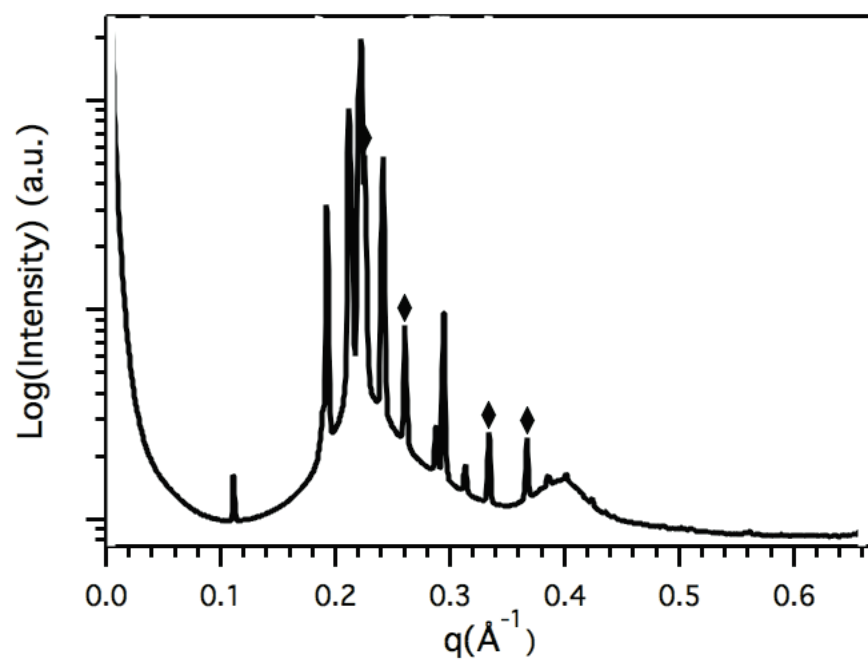


Fig. S3. Azimuthally-integrated X-ray scattering pattern for the aqueous LLC derived from 55.0 wt% **Na-74** in H₂O. Diamonds (♦) indicate the expected peak positions for the G_I phase that coexists with the H_I¹⁹³ phase.

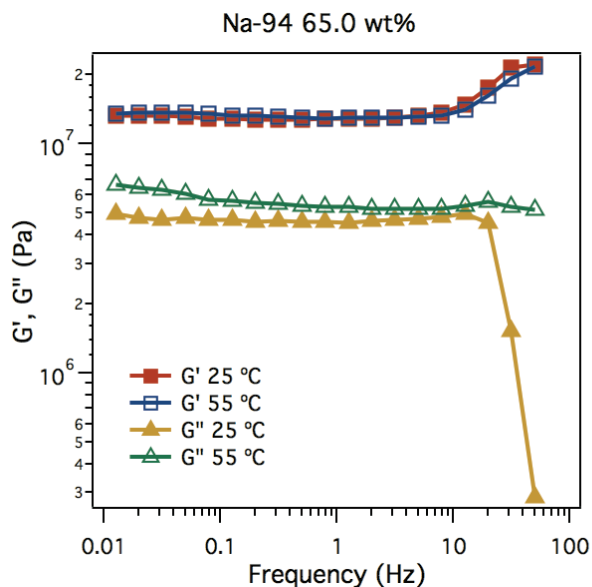


Fig. S4. Dynamic elastic storage (G') and loss (G'') modulus as a function of shear frequency for the G_I -phase comprising 65.0 wt% **Na-94** in H_2O at 25 and 55 °C.

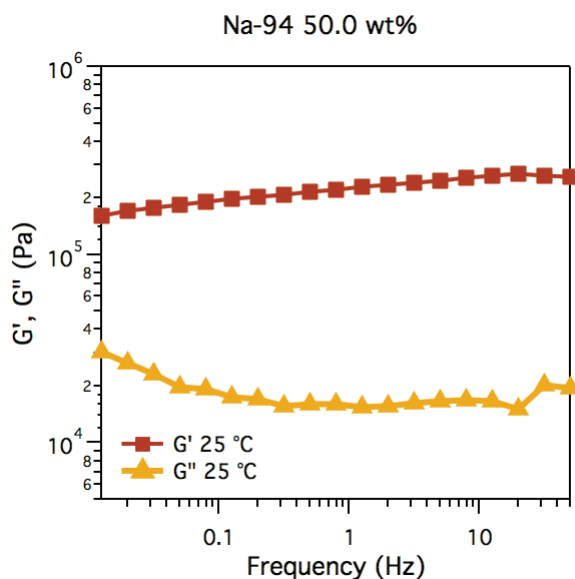


Fig. S5. Dynamic elastic storage (G') and loss (G'') modulus as a function of shear frequency for the C_I -phase comprising 50.0 wt% **Na-94** in H_2O at 25 °C. Attempts to obtain rheological data for this sample at 55 °C failed due to sample dehydration at elevated temperatures.

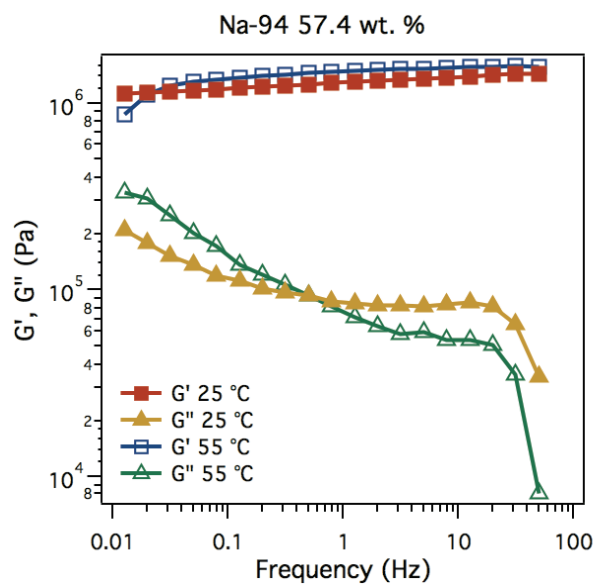


Fig. S6. Dynamic elastic storage (G') and loss (G'') modulus as a function of shear frequency for the H_I^{193} -phase comprising 57.5 wt% **Na-94** in H_2O at 25 and 55 °C.

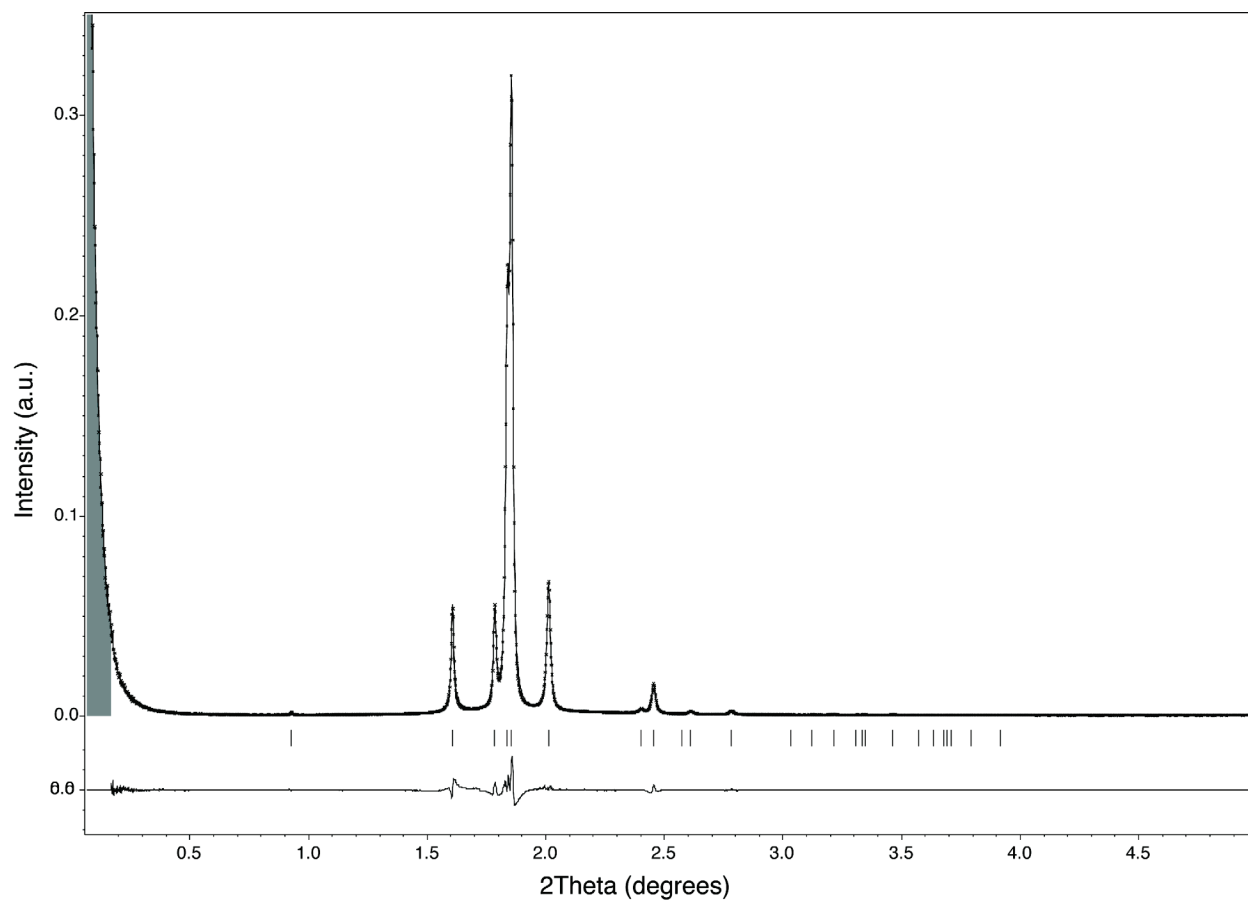


Fig. S7. Azimuthally-integrated X-ray scattering pattern for 57.5 wt% **Na-94** in H₂O at 40 °C overlaid with a simulated pattern from Rietveld refinement in *JANA2006*. Calculated peak positions and the fit residuals are displayed below the diffractogram. This fit assumes the $P6_3/mcm$ symmetry using lattice parameters $a = b = 7.34$ nm, $c = 6.60$ nm.

Table S2. List of structure factor intensities and peak full width at half maximum associated with each allowed reflection (hkl), derived from the fit shown in Fig. S7, as extracted by *JANA2006*.

(hkl)	Intensity	FWHM
1 0 0	4.4644	0.0074
1 1 0	1133.2637	0.0134
0 0 2	4084.4890	0.0156
1 1 1	3033.6406	0.0163
2 0 0	10000.0010	0.0165
1 0 2	1580.7277	0.0186
1 1 2	85.2785	0.0240
2 1 0	637.9702	0.0247
2 0 2	16.0249	0.0264
2 1 1	42.4498	0.0270
3 0 0	206.6376	0.0295
1 1 3	0.9880	0.0344
2 2 0	43.7681	0.0358
3 0 2	13.2740	0.0372
2 2 1	8.7943	0.0376
3 1 0	14.7810	0.0377
3 1 1	6.3111	0.0395
0 0 4	38.7469	0.0411
2 1 3	14.6813	0.0420
4 -2 2	17.3565	0.0427
1 0 4	18.1022	0.0429
4 0 0	47.1941	0.0432
3 1 2	0.1971	0.0444
1 1 4	52.9179	0.0463

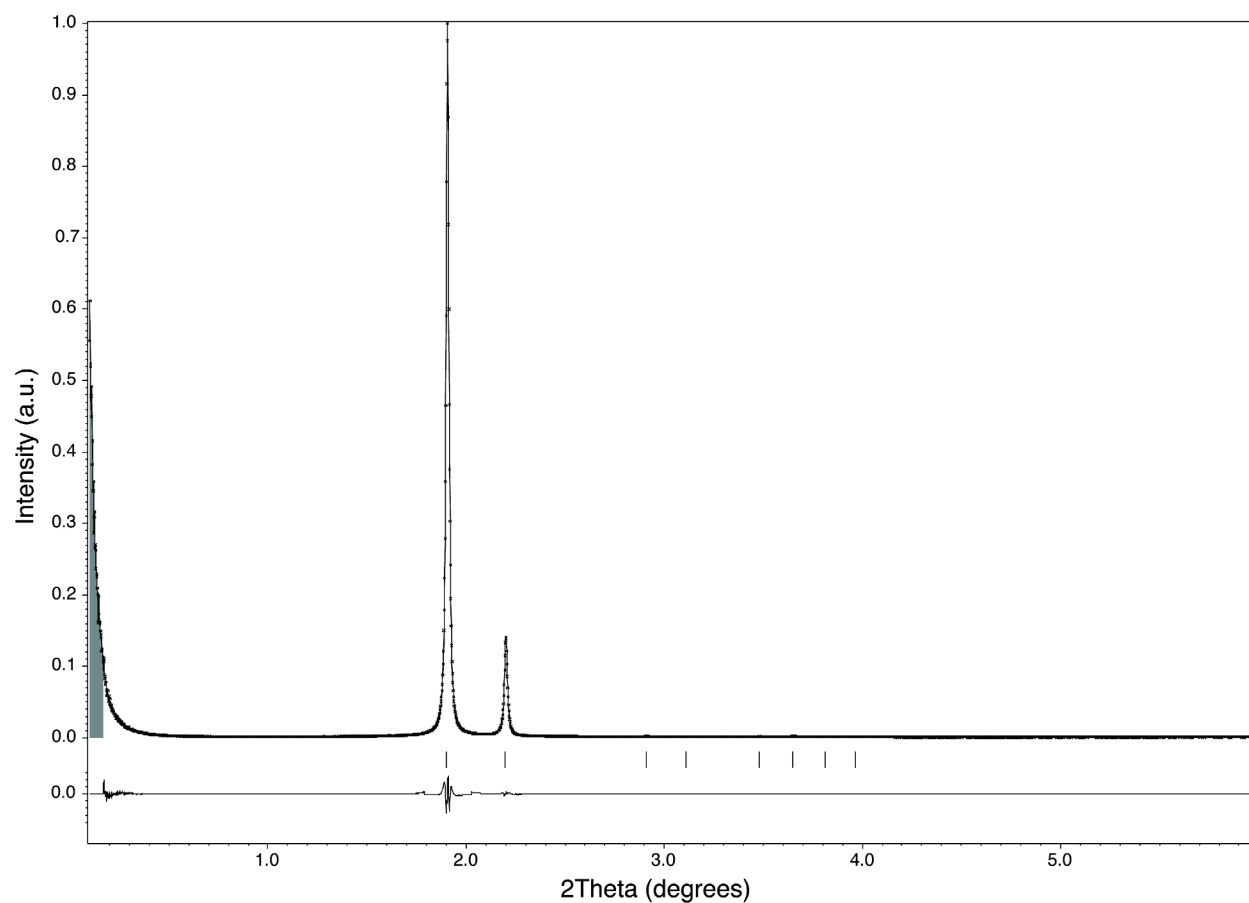


Fig. S8. Azimuthally-integrated X-ray scattering pattern for 62.5 wt% **Na-94** in H₂O at 40 °C overlaid with a simulated pattern from Rietveld refinement in *JANA2006*. Calculated peak positions and fit residual are displayed below the diffractogram. The fit was performed using *JANA2006* assuming $Ia\bar{3}d$ symmetry and resulting lattice parameters are $a = b = c = 7.53$ nm.

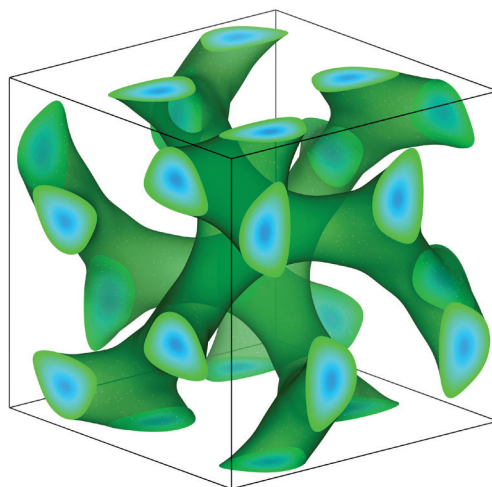


Fig. S9. Electron density reconstruction for G_I -phase comprising 62.5 wt% **Na-94** in H_2O at 40 °C using the Superflip charge flipping algorithm, derived from the fit shown in Fig. S8 with the lattice parameters $a = b = c = 7.53$ nm. This reconstruction serves to validate our use of the *SUPERFLIP* charge flipping algorithm for the reconstruction of the electron density maps for LLCs derived from gemini surfactants.

Figure S10. *SUPERFLIP* Text File Input for the generation of the electron density contrast map for the Hf^{193} phase shown in Fig. 3A is given below this line. *SUPERFLIP* implements a computer algorithm described in references 19 and 26 of the main article to generate an electron density reconstruction from the SAXS data by: (1) randomly assigning the initial phases associated with each observed reflection and generating a structure, (2) transforming the resulting structure into reciprocal space for comparison with the experimentally observed X-ray data, and (3) iteratively permuting the phases and comparing the results to the observed X-ray data, until a user defined convergence criterion is attained. The figure of merit associated with this electron density reconstruction was $\text{fm} = 15$, which is considered an excellent fit.

```

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perform CF
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outputformat jana
dimension 3
cell 73.3790 73.3790 66.0277 90.00 90.00 120.00
spacegroup P63/mcm
centro yes
centers
  0.000000 0.000000 0.000000
endcenters

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```

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  -x2  x1-x2      x3
 -x1+x2   -x1      x3
  -x1     -x2  x3+1/2
   x2 -x1+x2  x3+1/2
 x1-x2      x1  x3+1/2
   x2      x1 - x3+1/2
 x1-x2     - x2 -x3+1/2
  -x1 -x1+x2 -x3+1/2
  -x2     -x1     -x3
 -x1+x2      x2     -x3
   x1  x1-x2     -x3
  -x1     -x2     -x3
   x2 -x1+x2     -x3
 x1-x2      x1     -x3
   x1      x2 -x3+1/2
  -x2  x1-x2 -x3+1/2
 -x1+x2     -x1 -x3+1/2
  -x2     -x1  x3+1/2
 -x1+x2      x2  x3+1/2
   x1  x1-x2  x3+1/2
   x2      x1      x3

```

x1-x2	-x2	x3
-x1	-x1+x2	x3

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composition C14000 O2000

Keywords for charge flipping
repeatmode nosuccess
bestdensities 1 symmetry
polish yes
voxel auto
maxcycles 200000
delta AUTO
weakratio 0.000
Biso 0.000
randomseed AUTO
searchsymmetry average
derivesymmetry no
End of keywords for charge flipping

EDMA-specific keywords
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outputbase CleanHexNet
m40forjana yes
writem40 CleanHexNet_tmp.m40
maxima all
fullcell no
scale fractional
plimit 0.3000 sigma
numberofatoms composition
centerofcharge yes
chlimit 0.2500
chlimlist 0.1884 relative
End of EDMA-specific keywords

electrons 0.0000
dataitemwidths 4 15 15
dataformat intensity fwhm
fbegin

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2	-1	0	1133.2637	0.0134
0	0	2	4084.4890	0.0156
2	-1	1	3033.6406	0.0163
2	0	0	10000.0010	0.0165
1	0	2	1580.7277	0.0186
2	-1	2	85.2785	0.0240

3	-1	0	637.9702	0.0247
2	0	2	16.0249	0.0264
3	-1	1	42.4498	0.0270
3	0	0	206.6376	0.0295
2	-1	3	0.9080	0.0344
4	-2	0	43.7681	0.0358
3	0	2	13.2740	0.0372
4	-2	1	8.7943	0.0376
4	-1	0	14.7810	0.0377
4	-1	1	6.3111	0.0395
0	0	4	38.7469	0.0411
3	-1	3	14.6813	0.0420
4	-2	2	17.3565	0.0427
1	0	4	18.1022	0.0429
4	0	0	47.1941	0.0432
4	-1	2	0.1971	0.0444
2	-1	4	52.9179	0.0463

endf